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| Notice of References Cited | Application/Control No. 09/692,720 | Applicant(s)/Patent Under Reexamination SEKIGUCHI ET AL | |
| | Examiner Nhon T. Diep | Art Unit 2613 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,807,366 | 10-2004 | Okubo et al. | 386/124 |
| | B | US-6,741,793 | 05-2004 | Sugiyama, Akira | 386/68 |
| | C | US-6,654,544 | 11-2003 | Suzuki et al. | 386/112 |
| | D | US-6,643,729 | 11-2003 | Sasaki et al. | 711/4 |
| | E | US-5,835,144 | 11-1998 | Matsumura et al. | 375/240.23 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | Q | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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